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ALCHEMI OF NbCr₂/V C15-STRUCTURED LAVES PHASE

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Laves-phase intermetallics are of potential interest for use as high temperature structural materials, of which NbCr₂-based C15-structured Laves phases are particularly attractive.¹ Vanadium-alloyed NbCr₂ Laves phases have been studied.² The defect mechanism of a ternary Laves phase is crucial to understanding its physical metallurgy and deformation behavior.³ It is suggested based on the Nb-Cr-V phase diagram and first-principles total energy and electronic structure calculations for NbCr₂ that V should occupy the B sites in C15-structured AB₂.² In this paper, ALCHEMI⁴ is employed to examine this assumption for one composition of a V-alloyed NbCr₂ C15 Laves phase.

A Nb-Cr-V alloy of composition Nb₃₃Cr₄₂V₂₅ was prepared by arc-melting followed by annealing at 1400°C for 120 h. Specimens were prepared for microanalysis by cutting 3 mm discs followed by dimpling and ion milling. Energy-dispersive X-ray (EDX) spectra were acquired with a Philips CM30 operating at 300 kV and equipped with a KeveX Quantum detector. Fourteen spectra were collected near <014> over a range of {400} excitations between symmetry and beyond {12 0 0}. Owing to the high accelerating voltage (and therefore relatively flat Ewald sphere) used for these experiments, it was difficult to eliminate non-systematic reflections, although attempts were made to minimize this effect. Spectra were also acquired with a Philips CM12 operating at 120 kV and equipped with an EDAX superUTW detector. Nine spectra were collected near <334> over a range of {440} excitations between symmetry and {880}. Site-distributions were extracted from the data by multivariate statistical analysis (MSA)⁵ with delocalization correction⁶ as described elsewhere.^{7,8}

The C15 Laves phase structure is essentially the same as the oxide spinel structure without oxygen. Therefore, for the compound AB₂ (NbCr₂ in this case) there are two distinct sublattices: A (the tetrahedral site in spinel) and B (the octahedral site in spinel). Figure 1 shows X-ray spectra collected at {400} under conditions that maximized the electron fluence on the A and B sublattices. The correlated variation of the V and Cr characteristic X-ray peaks gives qualitative evidence of similar site-distributions for these elements. However, the precision of the site-distribution extracted with MSA was poor. This imprecision can be explained by the similarity of the variations of all X-rays to the channeling, as shown in Fig. 2. Although the variation of the Nb K α intensity is opposite to those of the V and Cr K α intensities, the shapes of the three curves are similar. The three curves do not therefore vary independently, as required by MSA. The lack of site-discrimination at {400} can be attributed to the similar elastic scattering powers of the alternating planes, of composition Nb and Cr₂ in the stoichiometric binary alloy. Indeed, the intensity of the 400 reflection was relatively weak. ALCHEMI was therefore performed at the {440} systematic row, with alternating planes of composition NbCr and Cr. Here, the intensity of the 220 reflection, due entirely to scattering from the A sublattice, was pronounced. Figure 3 shows the variation of the delocalization-corrected intensity ratios⁸ with orientation. The correction coefficients L_{CrX} were all within 2% of unity for the medium energy X-rays used for quantification. In contrast to the data in Fig. 2, the signals for the two host elements vary independently of one another. Multivariate statistical analysis indicated a 99.3 \pm 3.9% correlation between V and Cr. The relatively large statistical error arises because the two sublattices are not completely separated onto alternating planes at {440}.⁸ However, the result is consistent with exclusive site-occupancies of Nb for the A sublattice and Cr and V for the B sublattice.

In the C15 structure, the ideal ratio of atomic radii for the A and B sites is $\sqrt{3/2} \approx 1.225$. Ratios of ~ 1.1 to 1.6 are observed. In binary NbCr₂, the ratio of the Nb (2.08Å) to Cr (1.85Å) radii is ~ 1.13 . It is expected from size effects that V (1.92Å) would substitute for Nb on the A sublattice. As the V is found to substitute for Cr, it is clear that electronic effects must be more important than size effects in this case.⁹

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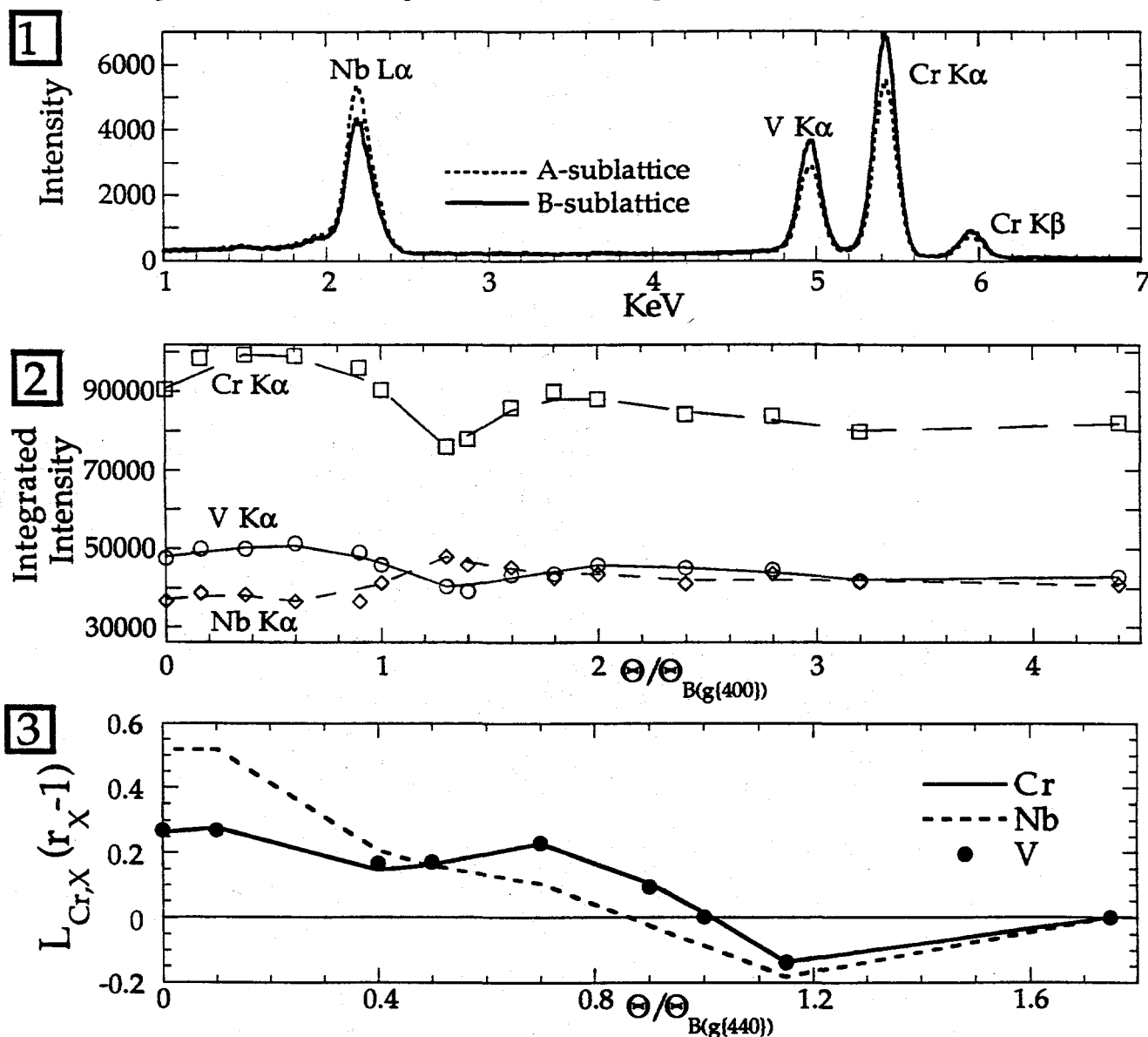


FIG 1 - EDX spectra acquired at {400} with electron fluence on the A and B sublattices.
 FIG 2 - Variation of integrated X-ray intensities with orientation at the {400} systematic row.
 FIG 3 - Variation of delocalization-corrected intensity ratios with orientation at the {440} systematic row.

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